

FPN530 FPN530A



NPN Low Saturation Transistor

These devices are designed for high current gain and low saturation voltage with collector currents up to 3.0 A continuous. Sourced from Process NC.

Absolute Maximum Ratings*

TA = 25°C unless otherwise noted

Symbol	Parameter	Value	Units CO	
V _{CEO}	Collector-Emitter Voltage	30	V	
V _{CBO}	Collector-Base Voltage	60	V	
V _{EBO}	Emitter-Base Voltage	5.0	V	
Ic	Collector Current - Continuous	3.0	Α	
T _J , T _{stg}	Operating and Storage Junction Temperature Range	-55 to +150	°C	

^{*}These ratings are limiting values above which the serviceability of any semiconductor device may be impaired.

1) These ratings are based on a maximum junction temperature of 150 degrees C.

2) These are steady state limits. The factory should be consulted on applications involving pulsed or low duty cycle operations.

Thermal Characteristics

TA = 25°C unless otherwise noted

Symbol	Characteristic	Max	Units
	- 17 [0]	FPN530 / FPN530A	
P _D	Total Device Dissipation	1.0	W
R _{θJC}	Thermal Resistance, Junction to Case	50	°C/W
R _{θJA}	Thermal Resistance, Junction to Ambient	125	°C/W



NPN Low Saturation Transistor

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TA = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Max	Units	
OFFICUAT						
OFF CHAI	RACTERISTICS					
BV _{CEO}	Collector-Emitter Breakdown Voltage	$I_C = 10 \text{ mA}, I_B = 0$	30		V	
BV _{CBO}	Collector-Base Breakdown Voltage	$I_C = 100 \mu A, I_E = 0$	60		V	
BV _{EBO}	Emitter-Base Breakdown Voltage	$I_E = 100 \mu A, I_C = 0$	5.0		V	
I _{CBO}	Collector Cutoff Current	$V_{CB} = 30 \text{ V}, I_{E} = 0$		100	nA	
		$V_{CB} = 30 \text{ V}, I_{E} = 0, T_{A} = 100^{\circ}\text{C}$		10	μΑ	
I _{EBO}	Emitter Cutoff Current	$V_{EB} = 4.0 \text{ V}, I_{C} = 0$		100	nA	
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ON CHARACTERISTICS*

h _{FE}	DC Current Gain	$I_C = 100 \text{ mA}, V_{CE} = 2.0 \text{ V}$	530	100		
			530A	250		
		$I_C = 1.0 \text{ A}, V_{CE} = 2.0 \text{ V}$		120		
		$I_C = 2.0 \text{ A}, V_{CE} = 2.0 \text{ V}$		80		
V _{CE(sat)}	Collector-Emitter Saturation Voltage	$I_C = 1.0 \text{ A}, I_B = 100 \text{ mA}$	530		300	mV
- ()			530A		250	mV
		$I_C = 2.0 \text{ A}, I_B = 200 \text{ mA}$			450	mV
V _{BE(sat)}	Base-Emitter Saturation Voltage	$I_C = 1.0 \text{ A}, I_B = 100 \text{ mA}$			1.25	V
V _{BE(on)}	Base-Emitter Saturation Voltage	I _C = 1.0 A, V _{CE} = 2.0 V			1.0	V

SMALL SIGNAL CHARACTERISTICS

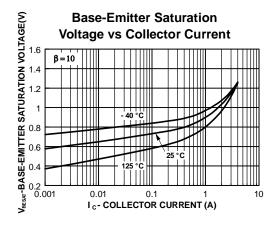
C _{obo}	Output Capacitance	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1.0 \text{ MHz}$		50	pF
F _T	Transition Frequency	$I_C = 100 \text{ mA}, V_{CE} = 5.0 \text{ V},$ f = 100 MHz	150		MHz

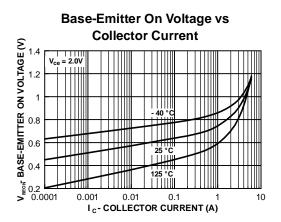
^{*}Pulse Test: Pulse Width \leq 300 μ s, Duty Cycle \leq 2.0%

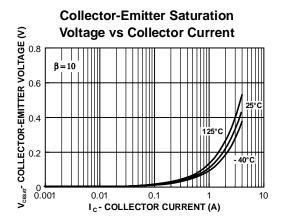
NPN Low Saturation Transistor

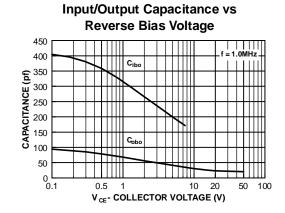
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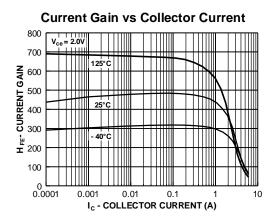
Typical Characteristics

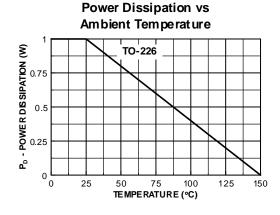












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